

Optocoupler with Phototransistor Output

Description

The CNY64/65/66 consist of a phototransistor optically coupled to a gallium arsenide infrared-emitting diode in a 4-lead plastic package.

The single components are mounted in opposite oneanother, providing a distance between input and output for highest safety requirements of > 3 mm.



Application

Circuits for safe protective separation against electrical shock according to safety class II (reinforced isolation):

- For application class I IV at mains voltage ≤ 300 V
- For application class I IV at mains voltage ≤ 600 V
- For application class I III at mains voltage ≤ 1000 V according to VDE 0884, table 2, suitable for:

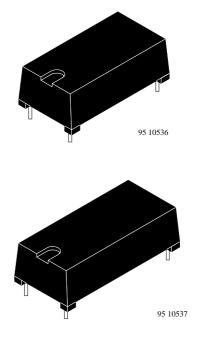
Switch-mode power supplies, computer peripheral interface, microprocessor system interface, line receiver.

These couplers perform safety functions according to the following equipment standards:

• VDE 0884/08.87

Optocoupler providing protective separation

- VDE 0804 Telecommunication apparatus and data processing
- VDE 0805/IEC 950/EN 60950
 Office machines (applied for reinforced isolation for mains voltage ≤ 400 V_{RMS})
- VDE 0860/IEC 65 Safety for mains-operated electronic and related household apparatus
- VDE 0700/IEC 335 Household equipment
- VDE 0160 Electronic equipment for electrical power installation
- VDE 0750/IEC 601 Medical equipment





Features

 Approvals: BSI: BS 415, BS 7002 FIMKO (SETI): EN 950 Underwriters Laboratory (UL) 1577 recognized-file No. E-76222 VDE 0884 Certificate number 76814

VDE 0884 related features:

- Rated impulse voltage (transient overvoltage) V_{I0TM} = 8 kV peak
- Isolation test voltage (partial discharge test voltage) V_{pd} = 2.8 kV peak
- Rated insulation voltage (RMS includes DC) V_{IOWM} = 1000 V_{RMS} (1450 V peak)
- Rated recurring peak voltage (repetitive) V_{IORM} = 1000 V_{RMS}
- Creepage current resistance according to VDE 0303/IEC 112 Comparative Tracking Index: (CTI) = 200
- Thickness through insulation > 3 mm

Absolute Maximum Ratings

Input (Emitter)

Parameters Test Conditions Symbol Value Unit Reverse voltage VR 5 V 75 Forward current mA I_{F} Forward surge current $t_p \le 10 \ \mu s$ 1.5 A I_{FSM} $T_{amb} \le 25^{\circ}C$ Power dissipation 120 mW P_{tot} Junction temperature 100 °C Ti

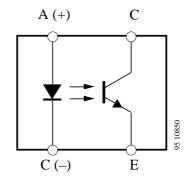
Output (Detector)

Parameters	Test Conditions	Symbol	Value	Unit
Collector emitter voltage		V _{CEO}	32	V
Emitter collector voltage		V _{ECO}	7	V
Collector current		IC	50	mA
Collector peak current	$t_p/T = 0.5, t_p \le 10 \text{ ms}$	I _{CM}	100	mA
Power dissipation	$T_{amb} \le 25^{\circ}C$	P _{tot}	130	mW
Junction temperature		Ti	100	°C

General features:

- Isolation materials according to UL94–VO
- Pollution degree 2 (DIN/VDE 0110 part 1 resp. IEC 664)
- Climatic classification 55/085/21 (IEC 68 part 1)
- Special construction: Therefore extra low coupling capacity typical 0.3 pF, high Common Mode Rejection
- Low temperature coefficient of CTR
- Current Transfer **R**atio (CTR) = 50 to 300%
- CNY64/65 also available in CTR groups A and B

Pin Connection



Coupler

Parameters	Test Conditions	Symbol	Value	Unit
AC isolation test voltage (RMS)		V _{IO}	8.2	kV
Total power dissipation	$T_{amb} \le 25^{\circ}C$	P _{tot}	250	mW
Ambient temperature range		T _{amb}	-55 to +85	°C
Storage temperature range		T _{stg}	-55 to +100	°C
Soldering temperature	2 mm from case, t \leq 10 s	T _{sd}	260	°C

Maximum Safety Ratings ¹) (according to VDE 0884)

Input (Emitter)

	Parameters Test Conditions Symbol Value Unit	Parameters
Forward current I _{si} 120	ent I _{si} 120 mA	Forward current

Output (Detector)

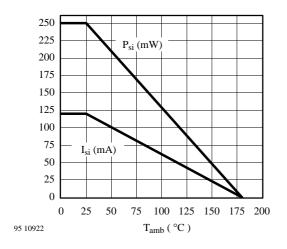
Parameters	Test Conditions	Symbol	Value	Unit
Power dissipation	$T_{amb} \le 25^{\circ}C$	P _{si}	250	mW

Coupler

Parameters	Test Conditions	Symbol	Value	Unit
Rated impulse voltage		V _{IOTM}	8	kV
Safety temperature		T _{si}	180	°C

¹⁾ This device is used for protective separation against electrical shock only within the maximum safety ratings. This must be ensured by using protective circuits in the applications.

Derating Diagram



Electrical Characteristics

$T_{amb} = 25^{\circ}C$

Input (Emitter)

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
Forward voltage	$I_F = 50 \text{ mA}$		V _F		1.25	1.6	V
Junction capacitance	$V_{R} = 0, f = 1 MHz$		Cj		50		pF

Output (Detector)

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
Collector emitter voltage	$I_C = 1 mA$		V _{CEO}	32			V
Emitter collector voltage	$I_E = 100 \ \mu A$		V _{ECO}	7			V
Collector emitter cut-off current	$V_{CE} = 20 \text{ V}, I_f = 0$		I _{CEO}			200	nA

Coupler

Parameters	Test Conditions	Туре	Symbol	Min.	Тур.	Max.	Unit
AC isolation test voltage (RMS)	f = 50 Hz, t = 1 s		V _{IO}	8.2			kV
Collector/emitter saturation voltage	$I_{\rm F} = 10 \text{ mA},$ $I_{\rm C} = 1 \text{ mA}$		V _{CEsat}			0.3	V
Cut-off frequency	$V_{CE} = 5 V,$ $I_F = 10 mA,$ $R_L = 100 \Omega$		f _c		110		kHz
Coupling capacitance	f = 1 MHz		Ck		0.3		pF
	$V_{CE} = 5 V_{r}$	CNY64 CNY65 CNY66		0.5	1	3	
$I_C \! / I_F$	$V_{CE} = 5 V,$ $I_F = 10 mA$	CNY64A CNY65A	CTR	0.63		1.25	
		CNY64B CNY65B		1		2	



Switching Characteristics (Typical Values)

 $V_S = 5 V$

Trino			$R_{L} = 10$	0Ω (see	figure 1)		$R_{L} = 1$	kΩ (see f	igure 2)
Туре	t _d [µs]	t _r [µs]	ton[µs]	t _s [µs]	t _f [µs]	t _{off} [µs]	I _C [mA]	t _{on} [µs]	t _{off} [µs]	I _F [mA]
CNY64, 65, 66	2.6	2.4	5.0	0.3	2.7	3.0	5	25	42.5	10

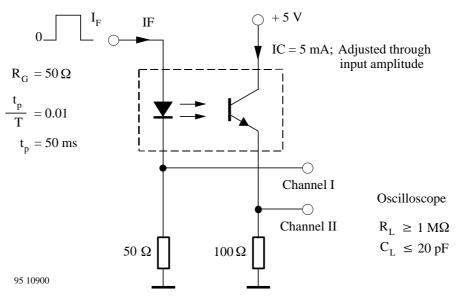


Figure 1. Test circuit, non-saturated operation

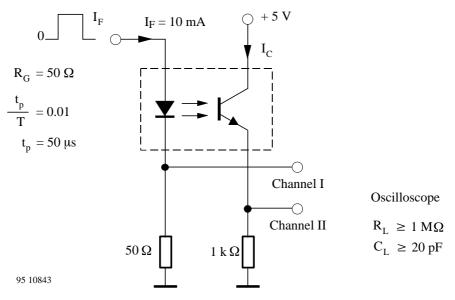


Figure 2. Test circuit, saturated operation

Insulation Rated Param	eters (according to VDE 0884)
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Paran	neters	Test Conditions	Symbol	Min.	Тур.	Max.	Unit
	Routine test	$10\% t_{test} = 1_S$	V _{pd}	2.8			kV
Partial discharge	Lot test (sample test)	$t_{Tr} = 10 \text{ s},$ $t_{test} = 60 \text{ s}$	V _{IOTM}	8			kV
lest voltage	test voltage (sample test)	(see figure 3)	V _{pd}	2.2			kV
		$V_{IO} = 500 \text{ V}$	R _{IO}	10 ¹²			Ω
Insulation resistance		$V_{IO} = 500 \text{ V},$ $T_{amb} = 100^{\circ}\text{C}$	R _{IO}	10 ¹¹			Ω
		$V_{IO} = 500 V$ $T_{amb} = 180^{\circ}C$	R _{IO}	10 ⁹			Ω
		(construction test only)					

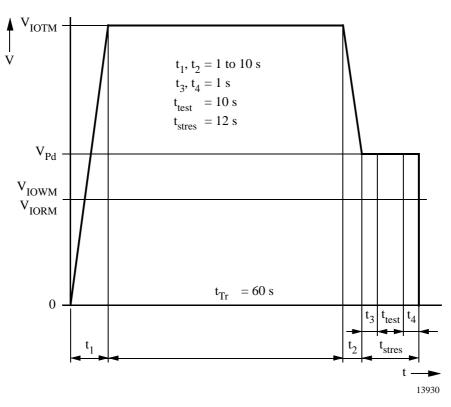


Figure 3. Test pulse diagram for sample test according to DIN VDE 0884

Typical Characteristics ($T_{amb} = 25^{\circ}C$, unless otherwise specified)

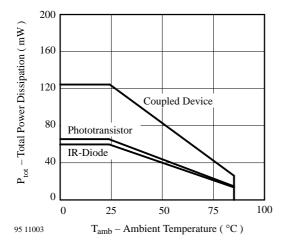


Figure 4. Total Power Dissipation vs. Ambient Temperature

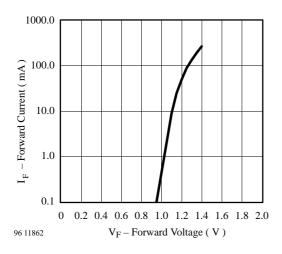


Figure 5. Forward Current vs. Forward Voltage

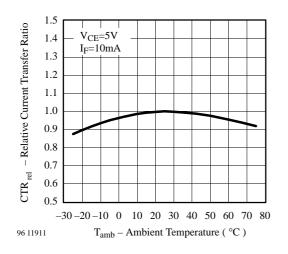


Figure 6. Rel. Current Transfer Ratio vs. Ambient Temperature

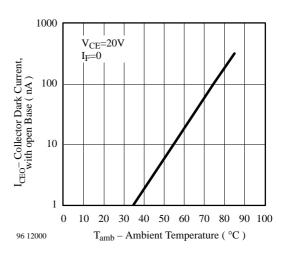


Figure 7. Collector Dark Current vs. Ambient Temperature

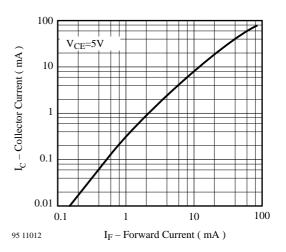


Figure 8. Collector Current vs. Forward Current

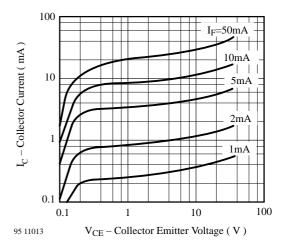


Figure 9. Collector Current vs. Collector Emitter Voltage

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Typical Characteristics ($T_{amb} = 25^{\circ}C$, unless otherwise specified)

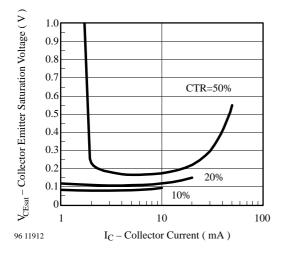


Figure 10. Collector Emitter Sat. Voltage vs. Collector Current

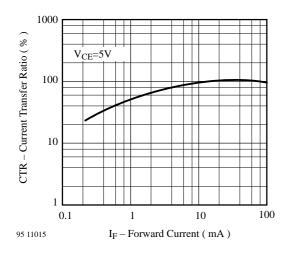


Figure 11. Current Transfer Ratio vs. Forward Current

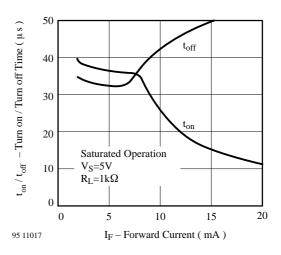


Figure 12. Turn on / off Time vs. Forward Current

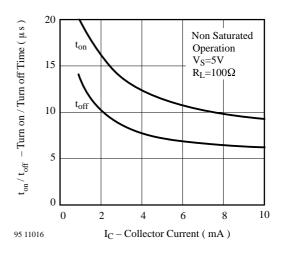
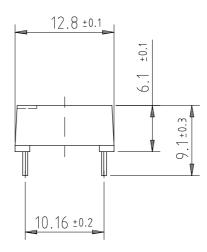
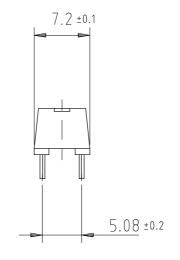


Figure 13. Turn on / off Time vs. Collector Current

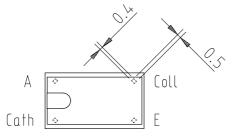


Dimensions of CNY64 in mm





14765





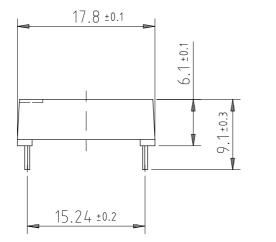
technical drawings according to DIN specifications

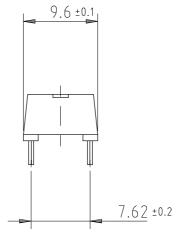
weight:	ca.	0.73 g
creeping di	≧ 9.5 mm	
air path:		≧ 9.5 mm

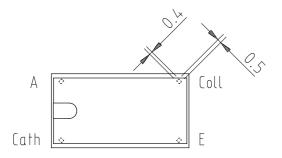
after mounting on PC board

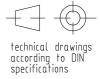


Dimensions of CNY65 in mm









1

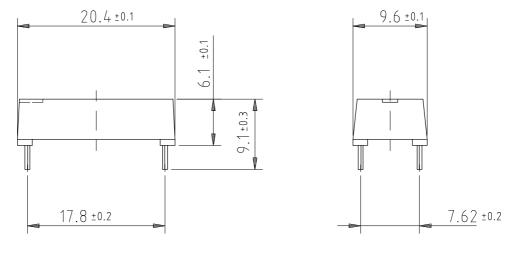
14763

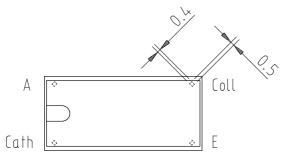
weight:	ca.	1.40 g
creeping distance:		≧ 14 mm
air path:		≧ 14 mm

after mounting on PC board



Dimensions of CNY66 in mm







technical drawings according to DIN specifications

14764

weight:	ca.	1.70 g
creeping distance:		≧ 17 mm
air path:		≧ 17 mm

after mounting on PC board

Ozone Depleting Substances Policy Statement

It is the policy of **TEMIC TELEFUNKEN microelectronic GmbH** to

- 1. Meet all present and future national and international statutory requirements.
- 2. Regularly and continuously improve the performance of our products, processes, distribution and operating systems with respect to their impact on the health and safety of our employees and the public, as well as their impact on the environment.

It is particular concern to control or eliminate releases of those substances into the atmosphere which are known as ozone depleting substances (ODSs).

The Montreal Protocol (1987) and its London Amendments (1990) intend to severely restrict the use of ODSs and forbid their use within the next ten years. Various national and international initiatives are pressing for an earlier ban on these substances.

TEMIC TELEFUNKEN microelectronic GmbH semiconductor division has been able to use its policy of continuous improvements to eliminate the use of ODSs listed in the following documents.

- 1. Annex A, B and list of transitional substances of the Montreal Protocol and the London Amendments respectively
- 2. Class I and II ozone depleting substances in the Clean Air Act Amendments of 1990 by the Environmental Protection Agency (EPA) in the USA
- 3. Council Decision 88/540/EEC and 91/690/EEC Annex A, B and C (transitional substances) respectively.

TEMIC can certify that our semiconductors are not manufactured with ozone depleting substances and do not contain such substances.

We reserve the right to make changes to improve technical design and may do so without further notice. Parameters can vary in different applications. All operating parameters must be validated for each customer application by the customer. Should the buyer use TEMIC products for any unintended or unauthorized application, the buyer shall indemnify TEMIC against all claims, costs, damages, and expenses, arising out of, directly or indirectly, any claim of personal damage, injury or death associated with such unintended or unauthorized use.

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